

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

B. Kim et al.

Attorney Docket No.: SEMT119849

Application No.: 10/700,782

Group Art Unit: 1753

Filed:

November 3, 2003

Examiner: Edna Wong

Title:

BATH AND METHOD FOR HIGH RATE COPPER DEPOSITION

INFORMATION DISCLOSURE STATEMENT

Seattle, Washington 98101

March 26, 2004

TO THE COMMISSIONER FOR PATENTS:

Applicants are aware of the information listed in the attached form that may be material to the prosecution of the above-identified patent application.

- 1. X Copies of the listed publications are enclosed for the Examiner's use.
- 2. X Pursuant to 37 C.F.R. § 1.97(b), this Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits.

Respectfully submitted,

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I hereby certify that this correspondence is being deposited with the U.S. Postal Service in a sealed envelope as first class mail with postage thereon fully prepaid and addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the below date.

Date: March 26, 2004

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FORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

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U.S. PATENT DOCUMENTS

*Examiner Initials	Cite No.	Document No.	Kind Code	Date (mm/dd/yyyy)	Name
	U1	1,526,644	A	02/17/1925	Pinney
	U2	1,881,713	A	10/11/1932	Laukel
	U3	3,267,010	A	08/16/1966	Creutz et al.
	U4	3,328,273	A	06/27/1967	Creutz et al.
	U5	3,664,933	A	05/23/1972	Clauss
	U6	3,706,635	Α	12/19/1972	Kowalski
	U7	3,716,462	A	02/13/1973	Jensen
	U8	3,770,598	Α	11/06/1973	Creutz et al.
	U9	3,878,066	Α	04/15/1975	Dettke et al.
	U10	3,930,363	Α	01/06/1976	Polichette et al.
	U11	4,000,046	A .	12/28/1976	Weaver
	U12	4,046,105	Α	09/06/1977	Gomez
	U13	4,134,802	Α	01/16/1979	Herr
	U14	4,272,335	Α	06/09/1981	Combs
	U15	4,279,948	Α	07/21/1981	Kukanskis et al.
	U16	4,304,641	Α	12/08/1981	Grandia et al.
	U17	4,384,830	Α	05/24/1983	Eckles
	U18	4,437,943	Α	03/20/1984	Beck et al.
	U19	4,500,394	Α	02/19/1985	Rizzo
	U20	4,576,689	Α	03/18/1986	Makkaev et al.

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 _ U21	4,624,749	Α	11/25/1986	Black et al.
 _ U22	4,634,503	Α	01/06/1987	Nogavich
 _ U23	4,648,944	A	03/10/1987	George et al.
 _ U24	4,781,800	Α	11/01/1988	Goldman et al:
_ U25	4,828,654	A	05/09/1989	Reed
_ U26	4,902,398	Α	02/20/1990	Homstad
 _ U27	4,949,671	Α	08/21/1990	Davis et al.
_ U28	4,959,278	Α	09/25/1990	Shimauchi et al.
 _ U29	4,988,533	Α	01/29/1991	Freeman et al.
 _ U30	4,990,224	A	02/05/1991	Mahmoud
 _ U31	5,000,827	Α	03/19/1991	Schuster et al.
 _ U32	5,021,129	A	06/04/1991	Arbach et al.
 _ U33	5,115,430	A	05/19/1992	Hahne et al.
 _ U34	5,116,430	A	05/26/1992	Hirai et al.
 _ U35	5,135,636	Α	08/04/1992	Yee et al.
_ U36	5,138,973	A	08/18/1992	Davis et al.
 _ U37	5,151,168	A	09/29/1992	Gilton et al.
_ U38	5,161,168	A	11/03/1992	Schilling
 _ U39	5,209,817	A	05/11/1993	Ahmad et al.
 _ U40	5,217,586	A	06/08/1993	Datta et al.
 _ U41	5,256,274	Α	10/26/1993	Poris
 _ U42	5,284,548	Α	02/08/1994	Carey et al.
 _ U43	5,302,464	A	04/12/1994	Nomura et al.
_ U44	5,344,491	A	09/06/1994	Katou
 _ U45	5,368,711	A	11/29/1994	Poris
 _ U46	5,372,848	A	12/13/1994	Blackwell et al.
 _ U47	5,376,176	A	12/27/1994	Kuriyama
 _ U48	5,391,285	A	02/21/1995	Lytle et al.
 _ U49	5,409,587	Α	04/25/1995	Sandhu et al.

·	_ U50	5,443,865	Α	08/22/1995	Tisdale et al.
	_ U51	5,472,502	A	12/05/1995	Lowery
	_ U52	5,472,592	Α	12/05/1995	Lowery
	_ U53	5,482,891	Α	01/09/1996	Shieh et al.
	_ U54	5,549,808	Α	08/27/1996	Farooq et al.
	_ U55	5,576,052	Α	11/19/1996	Arledge et al.
	_ U56	5,597,460	Α	01/28/1997	Reynolds
	_ U57	5,639,316	Α	06/17/1997	Cabral., Jr. et al.
	_ U58	5,674,787	Α	10/07/1997	Zhao et al.
	_ U59	5,681,392	A	10/28/1997	Swain
	_ U60	5,684,713	Α	11/04/1997	Asada et al.
	_ U61	5,695,810	Α	12/09/1997	Dubin et al.
	_ U62	5,719,447	Α	02/17/1998	Gardner
	_ U63	5,723,028	A	03/03/1998	Poris
	_ U64	5,723,387	Α	03/03/1998	Chen
	_ U65	5,730,854	Α	03/24/1998	Martin
	_ U66	5,750,018	A	05/12/1998	Brasch
	_ U67	5,754,842	Α	05/19/1998	Minagawa
	_ U68	5,824,599	A	10/20/1998	Schacham-Diamand et al.
	_ U69	5,871,626	A	02/16/1999	Crafts et al.
	_ U70	5,882,498	A	03/16/1999	Dubin et al.
	_ U71	5,891,513	A	04/06/1999	Dubin et al.
	_ U72	5,897,368	A	04/27/1999	Cole, Jr. et al.
	_ U73	5,908,543	A	06/01/1999	Matsunami et al.
	_ U74	5,913,147	A	06/15/1999	Dubin et al.
	_ U75	5,932,077	A	08/03/1999	Reynolds
	_ U76	5,969,422	Α	10/19/1999	Ting et al.
	_ U77	5,972,192	A	10/26/1999	Dubin et al.
	_ U 78	5,989,397	A	11/23/1999	Laube et al.

-	U79	5,989,406	Α	11/23/1999	Beetz, Jr. et al.
	U80	5,999,886	A	12/07/1999	Martin et al.
	U81	6,027,631	A	02/22/2000	Broadbent
	U82	6,028,986	A	02/22/2000	Song
	U83	6,036,836	A	03/14/2000	Peeters et al.
	U84	6,065,424	A	05/23/2000	Schacham-Diamand et al.
	U85	6,069,068	A	05/30/2000	Rathore et al.
	U86	6,074,544	A	06/13/2000	Reid et al.
	U87	6,090,260	A	07/18/2000	Inoue et al.
	U88	6,110,346	A	08/29/2000	Reid et al.
	U89	6,113,771	A	09/05/2000	Landau et al.
	U90	6,151,532	A	11/21/2000	Barone et al.
	U91	6,156,167	A	12/05/2000	Patton et al.
_	U92	6,159,354	A	12/12/2000	Contolini et al.
	U93	6,162,344	A	12/19/2000	Reid et al.
	U94	6,162,488	A	12/19/2000	Gevelber et al.
	U95	6,179,983	B1	01/30/2001	Reid et al.
	U96	6,193,859	B1	02/27/2001	Contolini et al.
	U97	6,197,181	B1	03/06/2001	Chen
	U98	6,197,688	B1	03/06/2001	Simpson
	U99	6,199,301	B1	03/13/2001	Wallace
	U100	6,228,232	B1	05/08/2001	Woodruff et al.
	U101 2	002/0042689	A1	06/20/2001	Chen
	U102	6,277,263	B1	08/21/2001	Chen
	U103	6,290,833	B1	09/18/2001	Chen
	U104	6,309,524	B1	10/30/2001	Woodruff et al.
	U105	6,319,831	B1	11/20/2001	Tsai et al.
	U106 2	002/0000382	A1	01/03/2002	Morrissey et al.
	U107 2	002/0008037	A1	01/24/2002	Wilson et al.

	U108	6,344,129	B1	02/05/2002	Rodbell et al.	
	U109	6,350,364	B1 02/26/2002		Jang	
	U110	2002/0043466	A1	04/18/2002	Dordi et al.	
•	U111	2002/0043468	A1	04/18/2002	Mikkola et al.	
<u> </u>	U112	6,391,166	B1	05/21/2002	Wang	
	U113	2002/0066673	A 1	06/06/2002	Rodbell et al.	
	U114	2002/0102837	A1	08/01/2002	Ritzdorf et al.	
	U115	6,565,729	B2	05/20/2003	Chen et al.	
		FORE	IGN PA	TENT DOCUME	<u>NTS</u>	
*Examiner	Cita		v:a D	ublication Date		English
Initial	No.	Document No.				Abstract Translation Provided Provided
	F1	GB 2 285 174		6/28/1995	GB	
	F2	JP 52-16433		07/30/1975	JP	X
	F3	WO 99/47731		09/23/1999	WO	
	F4	WO 02/45476	A2	06/13/2002	WO	
		(OTHER I	INFORMATION		
		_		le, Date, Pertinent	Pages, Etc.)	
*Examiner Initial	Cite No.					
	O1 Benedetti, A.V., et al., "Electrochemical Studies of Copper, Copper-Aluminum and Copper-Aluminum-Silver Alloys: Impedance Results in 0.5M NaCl," <i>Electrochimica Acta 40</i> :2657-2668, March 1995.					
	O2	Despić, A.R., "Deposition and Dissolution of Metals and Alloys, Part B: Mechanisms, Kinetics, Texture, and Morphology," in Brian E. Conway et al. (eds.), Comprehensive Treatise of Electrochemistry Vol. 7: Kinetics and Mechanisms of Electrode Processes, Plenum Press, New York and London, 1983, pp. 451-527.				
	O3	Dubin, V., et al., Copper Electroplating for On-chip Metallization, Advanced Micro Devices, Sunnyvale, CA. No date available.				

	O4	Dubin, V.M., et al., "Copper Plating Techniques For ULSI Metallization," Advanced Metallization and Interconnect Systems for ULSI Application in 1997, Proceedings of the Materials Research Society Symposium, San Diego,, September 30-October 2, 1997, pp. 405-411.
	O5	Gignac, L.M., et al., "Characterization of Plated Cu Thin Film Microstructures," Advanced Interconnects and Contacts, Vol. 564, Proceedings of the Material Research Society, San Francisco, , April 5-7, 1999, pp. 373-434.
	O6	Graham, L., et al., "Steady-State Chemical Analysis of Organic Suppressor Additives Used in Copper Plating Baths," <i>Proceedings of The Electrochemical Society</i> , Honolulu, October 17-22, 1999, pp.
	O7	Kang, S., et al., "Relationship Between Texture and Surface Morphology of Copper Electrodeposits," <i>Plating & Surface Finishing</i> , pp. 67-70, October 1995.
	O8	Kelly, J.J., and A.C. West, "Copper Deposition in the Presence of Polyethylene Glycol: I. Quartz Crystal Microbalance Study," <i>J. Electrochem. Soc. 145</i> (10):3472-3481, October 1998.
	O9	Khera, R.P., "The Basic Principles of Electrolytic Deposition," in Science and Technology of Surface Coating, Academic Press, New York, 1974, pp. 69-84.
	O10	Krishnan, R.M., et al., "Electroplating of Copper From a Non-Cyanide Electrolyte," <i>Plating & Surface Finishing 82</i> (7):56-59, July 1995.
	011	Lopatin, S., et al., "Extendibility of Ion-Metal Plasma and Electroplating Technologies for Damascene-Based Copper Metallization," <i>Proceedings of Advanced Metallization Conference</i> , Colorado, October 6-8, 1998, pp. 35-41.
	O12	Murarka, S.P., and S.W. Hymes, "Copper Metallization for ULSI and Beyond," <i>Critical Reviews in Solid State and Materials Sciences</i> 20(2):87-124, 1995.
	O13	Murarka, S.P., <i>Metallization: Theory and Practice for VLSI and ULSI</i> , Butterworth-Heinemann, Stoneham, Massachusetts, 1993.
	O14	Oskam, G., et al., "Electrochemical Deposition of Copper on n-Si/TiN," <i>J. Electrochem. Soc. 146</i> (4):1436-1441, 1999.
	O15	Reid, J.D., et al., "Impedance Behavior of Sulfuric Acid-Cupric Sulfate/Copper Cathode Interface," J. Electrochem. Soc.: Electrochemical Science and Technology 134(6):1389-1394. June 1987.

O16	Yung, E.K., and L.T. Romankiw, "Fundamental Study of Acid Copper Through-Hole Electroplating Process," <i>J. Electrochem. Soc.</i> 136(3):756-767, March 1989.
	Yung, E.K., et al., "Plating of Copper into Through-Holes and Vias," <i>J. Electrochem. Soc. 136</i> (1):206-215, January 1989.
Examiner	Date Considered
•=	

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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